

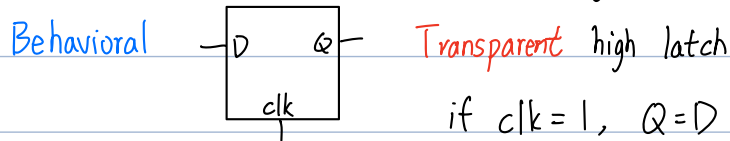
Latch sync.: clock ; async.: local handshake

:C waste on clk wait if finish early (dead time)

CSE clocked storage element 1. latch (level sensitive)

2. FF (edge triggered)

3. register (sys. level latch/FF)



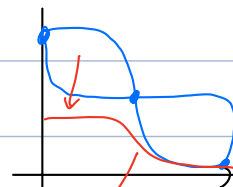
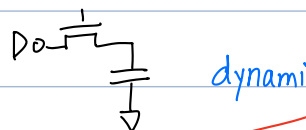
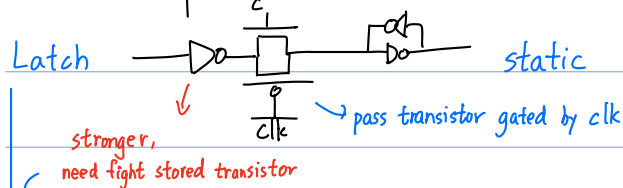
Timing t_{DQ} t_{CQ} (rising)

t_{setup} t_{hold} window before/after falling edge that D must be stable

Build 1. cross-coupled gates (pos. feedback)

3 op. points (2 stable)

2. cap. (leak)



Voltage transfer compressed $\downarrow$ $\rightarrow$ only one op

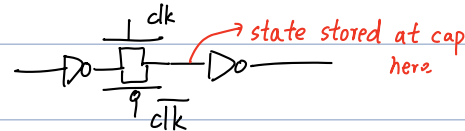
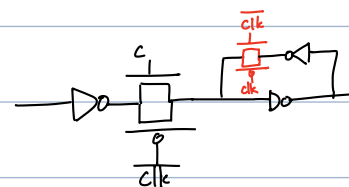
if too weak, not writable. Also fight $\rightarrow I_{crow}$

Want to shut feedback while writing. Gate w/ $\overline{clk}$

$\rightarrow$ gated feedback (not in SRAM, since want density)

D issue: leak (same w/ dyn. logic)

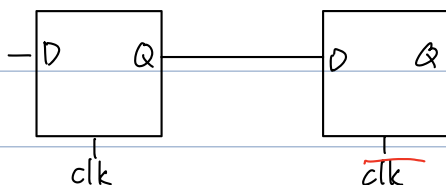
Not used any more



FF (edge)

param t_{CQ} , t_{setup} , t_{hold}

L1 L2
master-slave



@negedge, L1 closes, L2 opens

Late mode (long path)



$t_{CQ} + t_{setup} =$ latch overhead

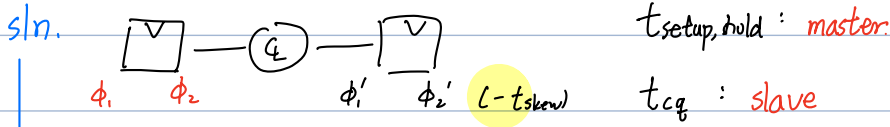
($\pm t_{skew} +$)

$$t_{CQ} + t_d + t_{setup} \leq T_{cycle}$$

Early mode (short path) $t_{cq} + t_d \geq t_{hold} (+ t_{skew})$ (E. shift register)

Short path padding w/ $\rightarrow 0$

Need indep. control of clk phase in ϕ/ϕ'

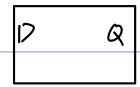
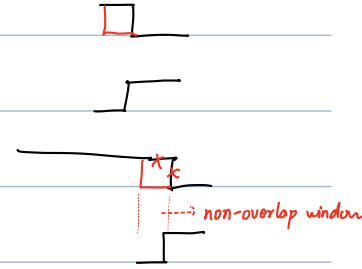


rising edge of slave $\rightarrow$ captured by falling $\sim$ of master

non-overlap window for all $\rightarrow$ master receive earlier

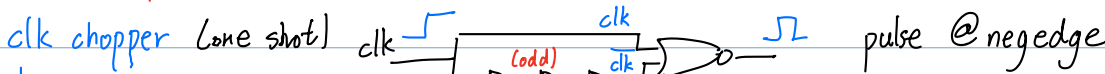
con: dead time at window $\rightarrow$ less time for long path $\rightarrow f_{max} \downarrow$

can be tuned in modern processor



Pulse mode clking (D-latch $\rightsquigarrow$ ff)

worse early m. issue ($+ t_{pulse}$) $\rightarrow$ two-sided constraints

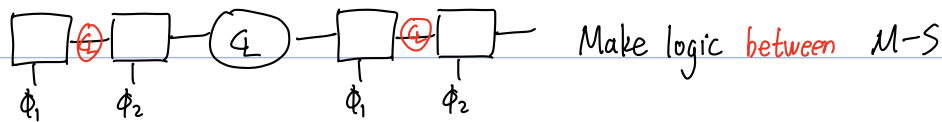


if global chop $\rightarrow$ distribute $\rightarrow$ runting.

if local chop $\rightarrow$ more gates $\therefore$

(separated)

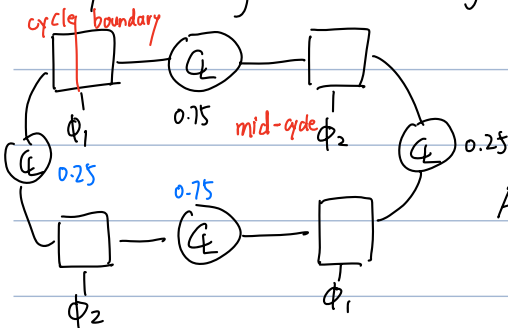
Transparent latch design



Long path 1. D must arrive before closing edge of any latch (assume $t_{setup}=0$) } global constraints

2. Loop latency $\leq$ # loop cycles

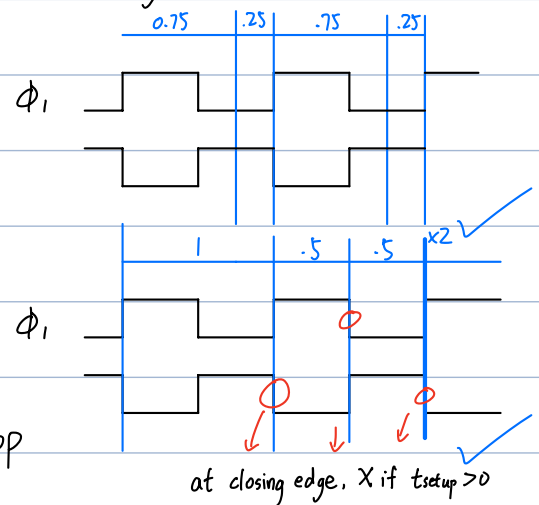
Cycle stealing: if one ϕ group too big, OK



Arbitrarily choose a starting point

Now 1, 0.5, 0.5, 0 (skewed)

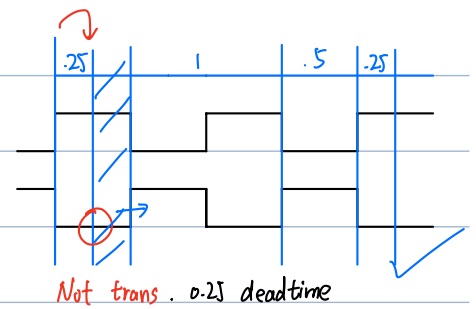
barely works, no deadtime, can stop



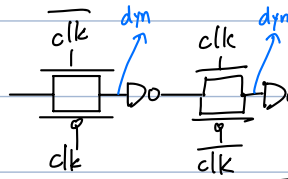
Now 0.25, 1, 0.5, 0.25 2.25 cycles > 2 , loop violation?

Data does not have to launch at CLK T. Can push 1st 0.25 back so cycle is still 2.25 $\rightarrow$ false violation ✓

Timing violation may not be local



Dyn. latch / FF (rare)

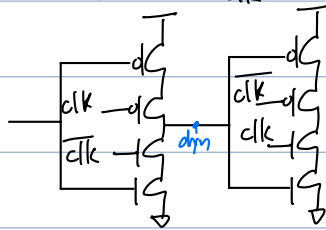


(master-slave) fast!

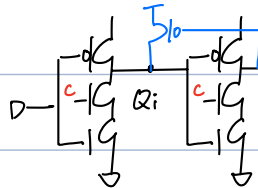
if clk, $\overline{\text{clk}}$ both 1, race, may flush

NDRA (no race, C² mos)

break connection w/ pt



TSPC (true single phase clocking)



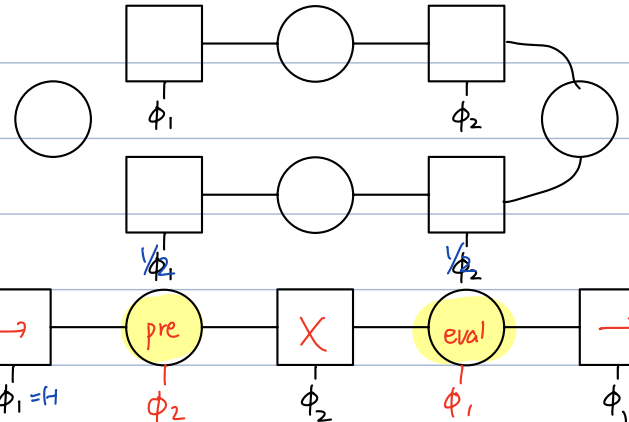
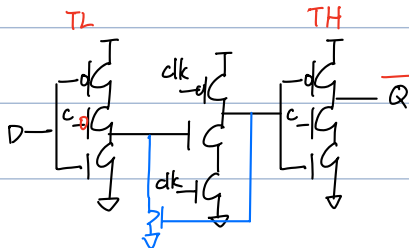
if $c=1$, $Q = \overline{Q} = D$

if $c=0$, opaque (dynamic if D or $Q_i = 1$)

either Q / Q_i dyn., but not both

FF (✓)

inverting



Dyn. flaw waste half of the cycle on pre

pipeline 2-phase, hide pre

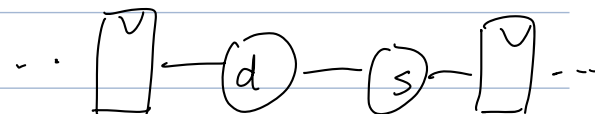
when $\phi_1 H$, ϕ_2 pre, closed

Partition issue. Need = :

If eliminate ϕ_2 latch. ϕ_2 prevents next to be corrupted by pre. Need value before pre.

Race ϕ_2 eval vs ϕ_1 pre, so mostly ϕ_2 latch still kept

Sta. mix dyn.



1. Static at end of any cycle, before pp

X: power. If FF outputs same $Q \rightarrow$ static $\star$; if diff $Q \rightarrow$ dyn. $\star$ (only switch once, hazard-free.)

static after dyn. is worst ————— (flutter when driven by dyn.)

Microprocessor (E. GPU, ...)

1. Data path: logic blocks handling/op. data (E. adder, shifter, register)

2. Control (random logic, not structured)

tend buggy : C

3. Arrays: memory (very structured) (E, RF, SRAM, embedded DRAM)

Num [★] fixed point (int), ¹ signed, ^{2'sc} unsigned

f_p (mantissa + exp), f_{pu}

2's c overflow = $C_n \oplus C_{n-1}$

endian in virtuoso, make bus $a \langle 0:31 \rangle$

(i) $a \langle 31:0 \rangle$

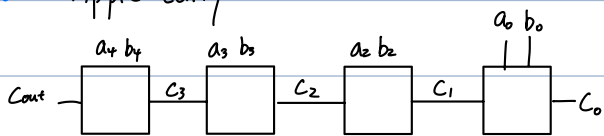
big $a\langle 0:31 \rangle$

Adder (FA) $S = a \oplus b \oplus c_{in}$

$$C_{out} = ab + ac_{in} + bc_{in} \quad (\text{majority})$$

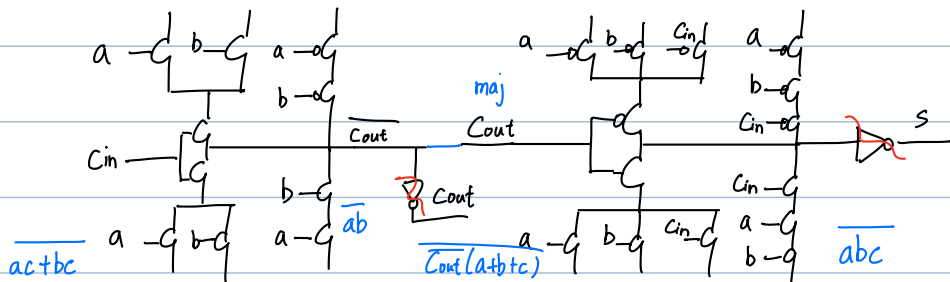
self dual $\bar{s}(a, b, c_m) = s(\bar{a}, \bar{b}, \bar{c}_m)$ } if building push-pull, identical pun, pdn
 $\bar{c} \sim = c(\sim, \sim)$ } great for layout

E. 8-bit ripple carry



for ripple, s_3 slowest

layout : just FA, and tile it well

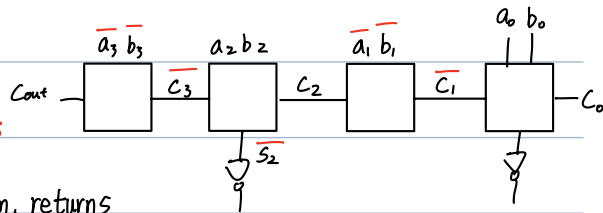


Can make generate Count and sum, alternate inverting inputs

Sizing

... want $w \rightarrow \infty$, dim. returns

load in C by S circuit



S not in crit. path, make $S \downarrow \rightarrow$ size C chain (same size)

sub invert B, $C_{in} = 1$

Parallel $C_{out} = ab + ac_{in} + bc_{in}$

$$\equiv g + pC_{in}$$

$$g \equiv ab, p \equiv a \oplus b \rightarrow s = p \oplus C_{in}$$

1. Carry bypass E. break 16-bit into 4x4

MUX, set bit ANDs all $p_i = a_i \oplus b_i$

E. $n=16$ $t_{\text{crit}} \approx 3t_{\text{max}} + 2.4 t_{\text{ripple}}$

2. Carry select E. 4×4

Calculate all carries if C_{in} is 0; if $C_{in} = 1$

use MUX to select

$$t_{\text{cnt}} = t_{\text{pg}} + t_{\text{carry}_0} + t_{\text{carry}_1} + 4t_{\text{max}} + t_{\text{sum}}$$

3. CLA

$$C_{i+1} = g_i + p_i C_i$$

$$= \overbrace{g_i + p_i g_{i-1} + p_i \dots p_i g_0}^G + \overbrace{p_i \dots p_0 c_0}^P$$

E.4 : radix-4 lookahead

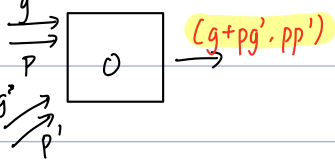
E.16 can take 4x radix 4 & ripple :C

Hierarchical $P_0 \equiv p_3 p_2 p_1 p_0 \text{ cin}$

$$G_0 \equiv g_3 + p_3 g_2 + p_3 p_2 g_1 + p_3 p_2 p_1 g_0$$

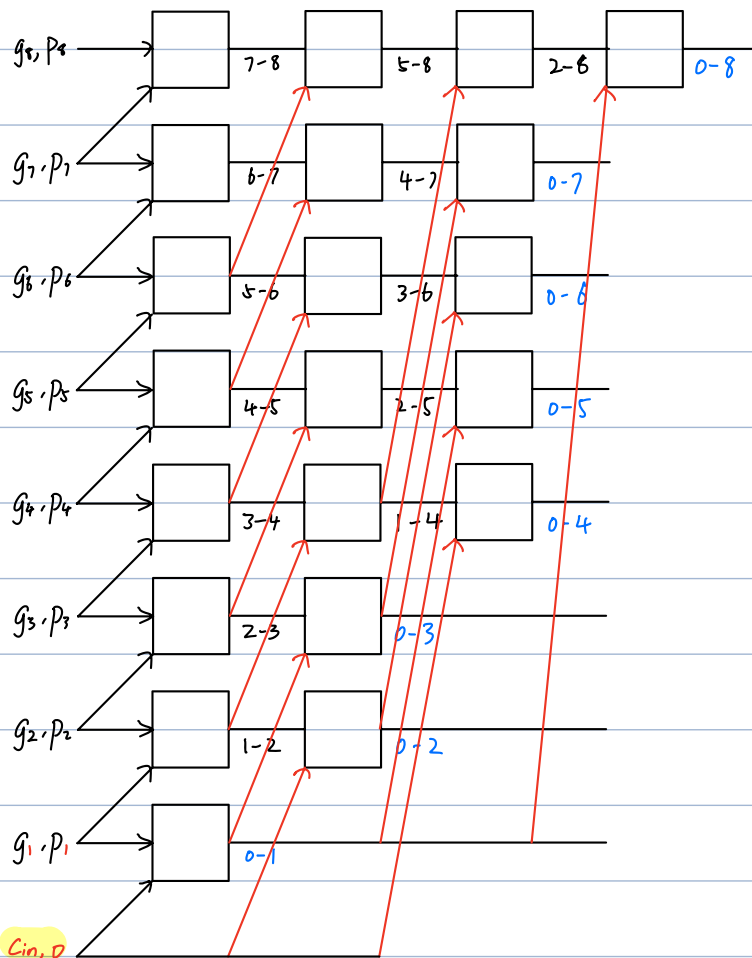
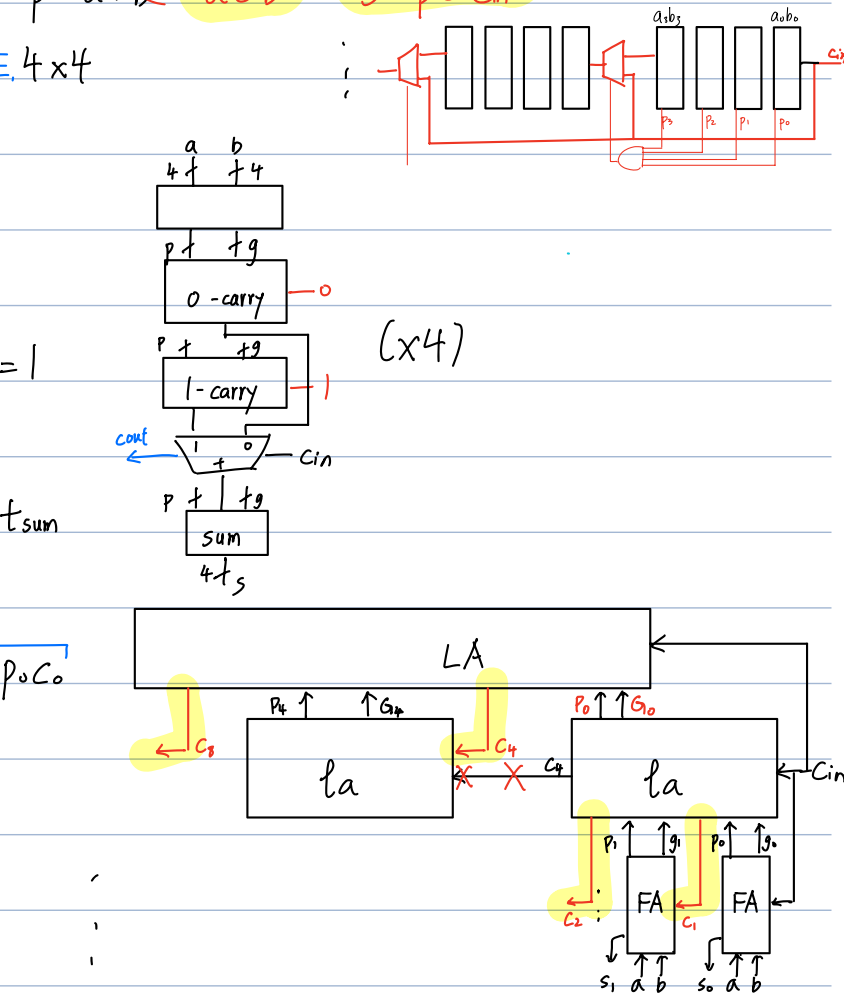
tree adders (radix-4). Radix 2 is simpler.

Radix-2

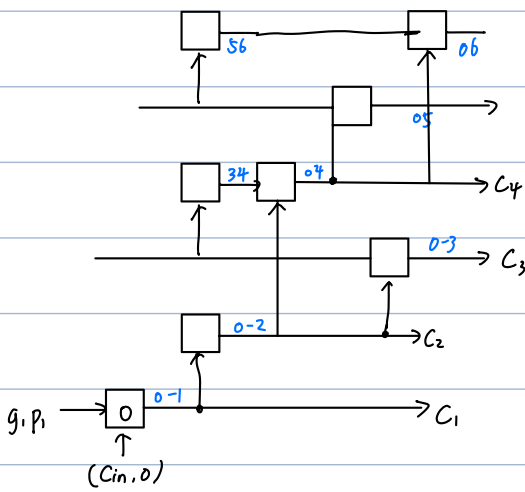


KS 0-1-2-4

for 1 or 2!

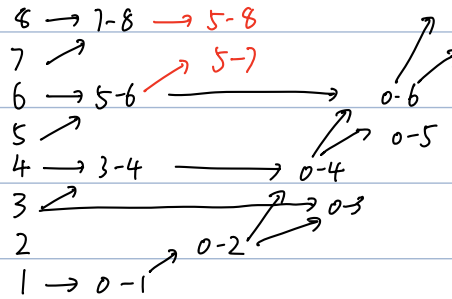


BK



area efficient, but not same fanout

harder to layout



even bits grabbed

Shifter 1. logical always pad 0 (shamt)

2. arithmetic pad MSB (sext) when shift right

logarithmic shifter

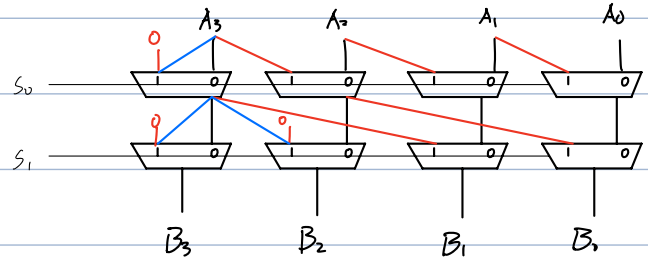
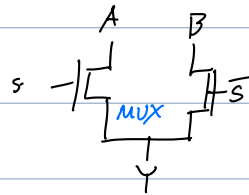
$s = \text{shamt}$

if s_2 , need shift by 4.

if arithmetic, shift in msb

stack = 2 + 1 (input inverter) : (

can buf w/ D0



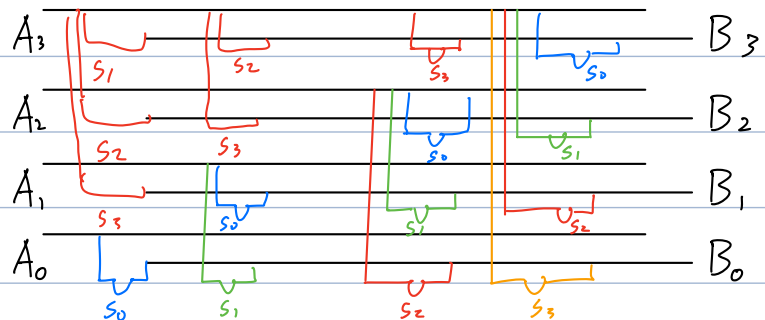
Barrel shifter (pt) (4-bit)

shamt: 1-hot $s_{3:0}$

arith $\Rightarrow$

2 stack height *

need $\perp$



Rotator out $\rightarrow$ in

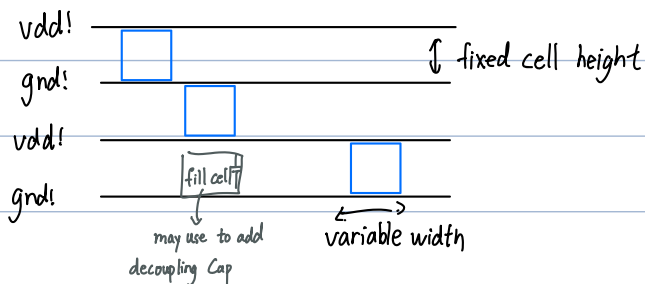
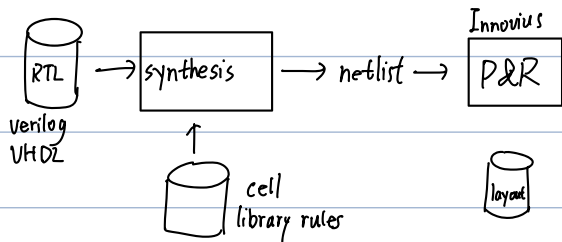
Control

1. random logic → multi-level → semi-custom

2. structured logic (PLA) programmable logic array, area ineff.

1. RTL (structured, careful) → logic synthesis tool ^{layout} → P&R ^{place route}

cells (lib) → static timing analysis



P&R uses feedback to optimize

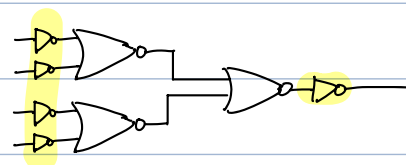
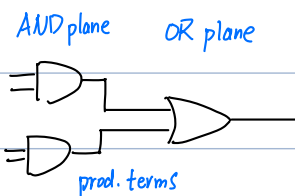
PLA ^{programmable logic array} structured (E. instr. decode)

Two-level logic: SoP, PoS

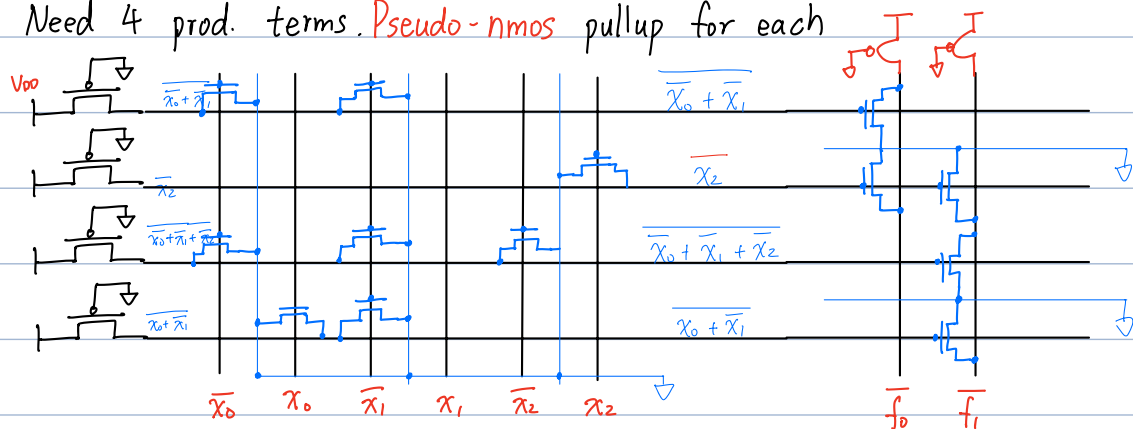
Espresso: minimize SoP terms (heuristic)

bubble pushing AND-OR ⇒ NOR-NOR

Static PLA E. $f_0 = x_0 x_1 + \bar{x}_2$, $f_1 = x_0 x_1 x_2 + \bar{x}_2 + \bar{x}_0 x_1$



Need 4 prod. terms. Pseudo-nmos pullup for each



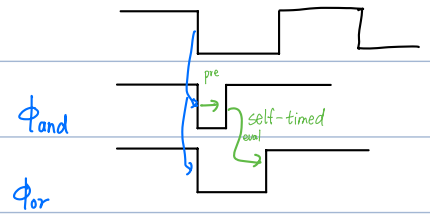
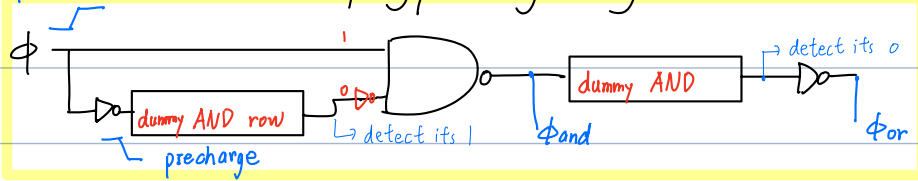
Espresso format	(noninverted) AND plane			OR plane		Espresso →
	x_0	x_1	x_2	f_0	f_1	
	1	1	-	1	0	
0: use $\bar{x}$	-	-	0	1	1	
1: use x	1	1	1	0	1	
-: d.c.	0	1	-	0	1	

Dynamic PLA dyn. nor — dyn. nor (turn pseudo-n into clked)

but no $\overline{D_0}$ available for domino $\rightarrow$ clk w/ ϕ_{AND} , ϕ_{OR} . Don't start ϕ_{OR} before AND eval'd.

self-timed $\rightarrow$ need delay elements

Replica: same circuit topology, timing testing

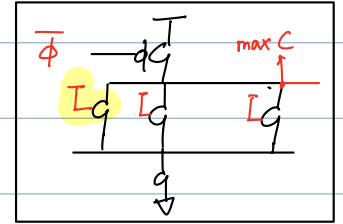


Layout dummy and row exact same. Load w/ slowest precharge time

(large C on precharge node E. 3 nfets, all inputs high)

slow eval put 1 input high, rest 0

wait for output to be eval'd to 0 $\rightarrow \phi_{or} \nabla$



Testing

$I_{DD,0}$ I_{DD} at quiescent (some leak, but can't be huge)

Shut any static current (E. analog, half latch)

Memory (array) SDRAM (volatile)

D trench into Si (deep reactive ion etching) → Cap

S row decoder: wordlines (demux 1-hot)

col mux: bitlines
10b

Logical organization E. 1024 × 64

Physical E. 256 × 256
8b 8b
2b addr. to col. mux
8b to row dec.

Cell (6T)

R 1. precharge bit, bit
(row dec)

2. select 1 wordline (access on for word)

3. state pulls low bit or $\overline{\text{bit}}$

4. detect (don't want to wait all the way → 0, slow, power)

issue R may upset cell (read stability)

at precharge, both sides V_{DD} , DO can't go all → 0. (wing stability)

Need access transistor to 1.5~2x smaller than D_{on} .

W 1. precharge

2. sel. wordline

3. Pull bit/ $\overline{\text{bit}}$ down → flip SRAM

issue W writability (want diagram to collapse)

access T 3x stronger than D_{on}

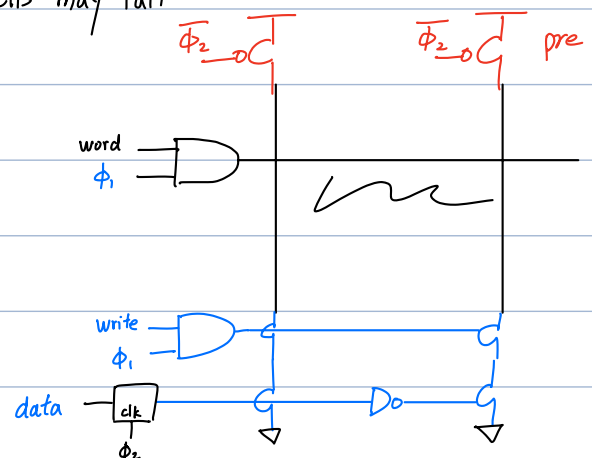
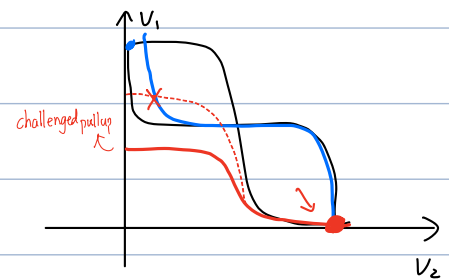
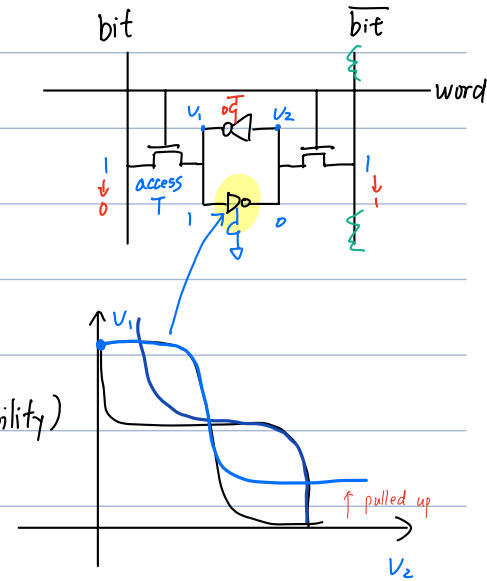
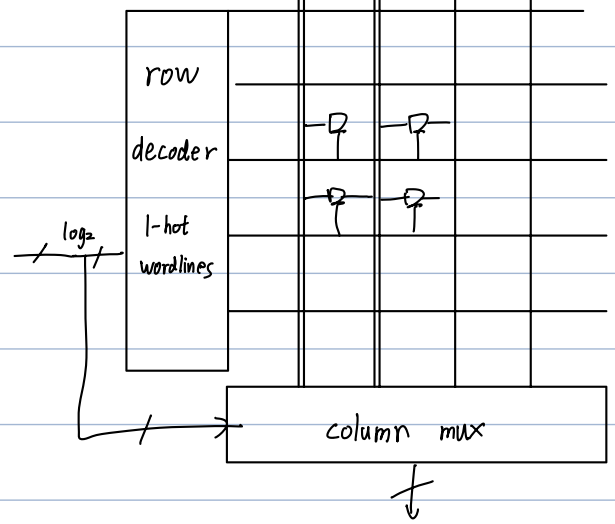
Sizing by changing L and W. → dense

Layout w/ push rules (denser DRC)

small → dopant variation → V_T w → strength ~ → cells may fail

sln. 1. when not accessing, run at $< V_{DD}$. Only V_{DD} @ reading

2. redundancy (E columns), take out if bad



Peripheral self timed; or ϕ_1, ϕ_2

R 1. pre @ $\phi_2 = 1$

2. access @ $\phi_1 = 1$ (clk qualification)

detect : skewed $\overline{D_0}$ (single-ended)

W some pre, access clk

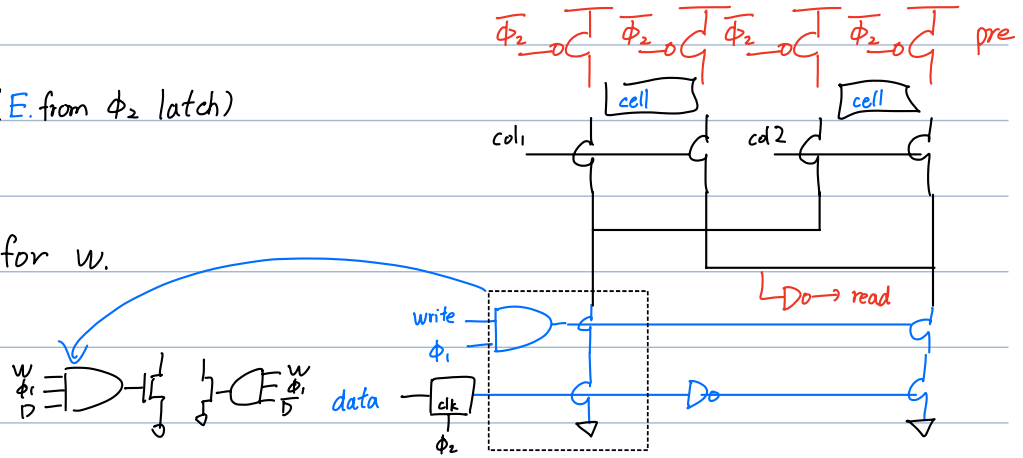
data needs to be ϕ_1 -stable (E. from ϕ_2 latch)

3-high stack

+ Mux column mux gives more space for w.

4-high stack

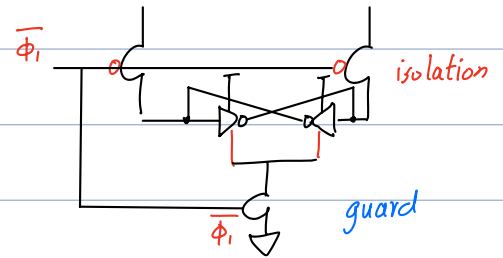
sln. combine 2-stack AND logic



SA (differential read)

limited by GBW $\rightarrow$ regenerative circuits

need know when to amplify $\rightarrow$ clk



access iso on, guard off ($\overline{D_0}$ off), one low

pre : iso off, guard on, $\overline{D_0}$ amplify w/ regenerative feedback

issue if inv. not exact same, $\overline{D_0}$ offset $\rightarrow$ flip to wrong state

Inverters w/ regenerative feedback not limited by GBW issue $\rightarrow$ fast, but need clk.

Decoder (glorified AND) E.3 $\rightarrow$ 8: 8 ANDs

issue: input $\uparrow$, high $\rightarrow$ multilevel

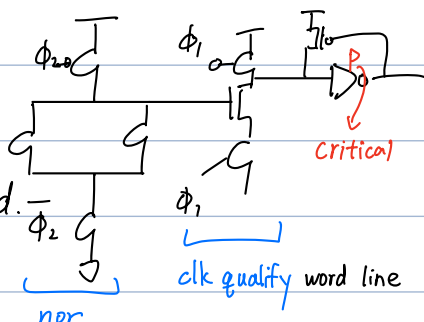
Final output match SRAM roles $\rightarrow$ special DR for dec.

Typically dynamic nor:

race-based nor

Make ϕ_1 delay ϕ_2 to avoid race cond.

$\overline{D_0}$ pfet critical $\rightarrow$ need wide fingers



predecoder decoder

